

## Silicon Field Stop(FS) Trench IGBT

### Description

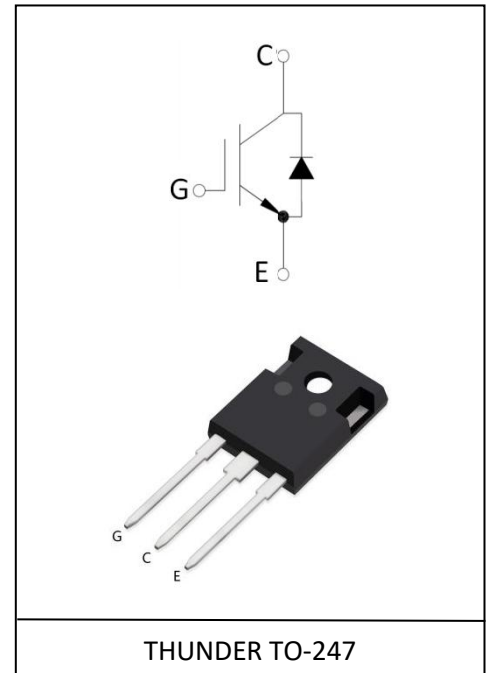
The THG40T65FQK is use advanced field stop(FS) trench technology. The 650V FS Trench IGBT offers superior conduction and switching performances.

### General Features

- High Speed Switching & Low Power Loss
- Low saturation voltage:  $V_{CE(sat)} = 1.8V @ I_c = 40A$
- $E_{off} = 0.3mJ @ T_c = 25^{\circ}C$
- Maximum junction temperature  $175^{\circ}C$

### Application

- Solar Converters
- Welding Converters
- UPS
- PFC
- PV Inverter



### Absolute Maximum Ratings @ $T_c=25^{\circ}C$ (unless otherwise specified)

Symbol	Parameter	Value	Unit
$V_{CES}$	Collector-Emitter Voltage	650	V
$V_{GES}$	Gate-Emitter Voltage	$\pm 20$	V
$I_c$	Collector Current	80	A
	Collector Current @ $T_c=100^{\circ}C$	40	A
$I_{CM}$	Pulsed Collector Current	160	A
$I_F$	Diode Continuous Forward Current @ $T_c=100^{\circ}C$	40	A
$I_{FM}$	Diode Maximum Forward Current	160	A
$P_D$	Total Dissipation at @ $T_c = 25^{\circ}C$	280	W
	Total Dissipation at @ $T_c = 100^{\circ}C$	140	
$T_j$	Operating Junction and Storage Temperature Range	-55 to +175	$^{\circ}C$
$T_L$	Max Temperature For Soldering	260	$^{\circ}C$
$T_{SC}$	Short circuit withstand time $V_{GE}=15V, V_{CC} \leq 400V$ , Allowed number of short circuits<1000Time between short circuits: $\geq 1.0s, T_j \leq 150^{\circ}C$	5	us

**Electrical Characteristics @ T<sub>c</sub>=25°C (unless otherwise specified)**

Symbol	Parameter	Test Conditions	Min	Typ	Max	Unit
<b>Static Characteristics</b>						
V <sub>CE(S)</sub>	Collector-Emitter Voltage	V <sub>GE</sub> =0V, I <sub>CE</sub> =250μA	650	—	—	V
V <sub>CE(sat)</sub>	Collector-Emitter Saturation Voltage	V <sub>GE</sub> =15V, I <sub>C</sub> =40A	—	2	2.30	V
V <sub>GE(th)</sub>	Gated Threshold Voltage	V <sub>CE</sub> =V <sub>GE</sub> , I <sub>C</sub> =1mA	3.5	4.5	6.5	V
I <sub>CE(S)</sub>	Collector-Emitter Leakage Current	V <sub>GE</sub> =0V, V <sub>CE</sub> =650V	—	—	10	uA
I <sub>GES(F)</sub>	Gate to Emitter Forward Leakage	V <sub>GE</sub> = +20V, V <sub>CE</sub> = 0V	—	—	200	nA
I <sub>GES(R)</sub>	Gate to Emitter Reverse Leakage	V <sub>GE</sub> = -20V, V <sub>CE</sub> = 0V	—	—	-200	nA
<b>Dynamic Characteristics</b>						
C <sub>ies</sub>	Input Capacitance	V <sub>GE</sub> =0V, V <sub>CE</sub> =25V, f=1.0MHZ	—	1828	—	pF
C <sub>oes</sub>	Output Capacitance		—	140	—	pF
C <sub>res</sub>	Reverse Transfer Capacitance		—	48	—	pF
Q <sub>g</sub>	Total Gate Charge	V <sub>CE</sub> =480V, I <sub>C</sub> =40A, V <sub>GE</sub> =15V	—	186	—	nC
Q <sub>ge</sub>	Gate to Emitter Charge		—	42	—	
Q <sub>gc</sub>	Gate to Collector Charge		—	76	—	
<b>Switching Characteristics</b>						
t <sub>d(on)</sub>	Turn-on Delay Time	V <sub>CE</sub> =400V, I <sub>C</sub> =40A V <sub>GE</sub> =15V, R <sub>G</sub> =10Ω	—	79	—	nS
t <sub>r</sub>	Rise Time		—	68	—	
t <sub>d(off)</sub>	Turn-off Delay Time		—	114	—	
t <sub>f</sub>	Fall Time		—	59	—	
E <sub>on</sub>	Turn-on Energy		—	3.4	—	mJ
E <sub>off</sub>	Turn-off Energy		—	0.2	—	
E <sub>tot</sub>	Total Switching Energy		—	3.6	—	

**Electrical Characteristics of the Diode @T<sub>c</sub>= 25°C unless otherwise specified**

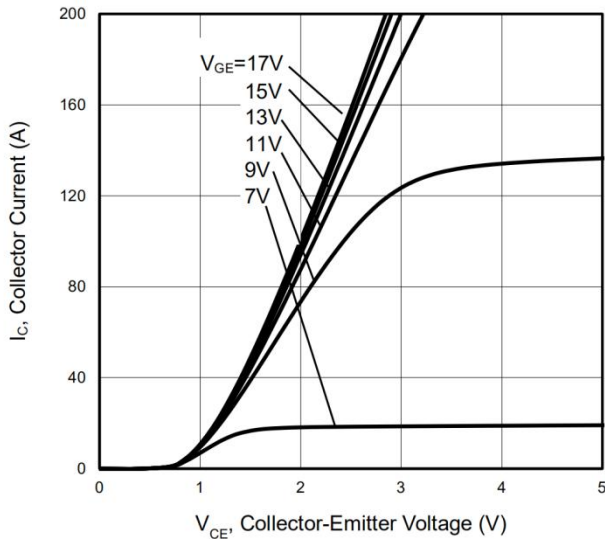
Symbol	Parameter	Test Conditions	Min	Typ	Max	Unit
I <sub>F</sub>	Diode Continuous Forward Current	T <sub>C</sub> = 100°C	40	—	—	A
I <sub>FM</sub>	Diode Maximum Forward Current	T <sub>C</sub> = 100°C	200	—	—	A
V <sub>F</sub>	Diode Forward Voltage	I <sub>F</sub> = 40A	—	1.85	2.25	V
t <sub>rr</sub>	Reverse Recovery Time	T <sub>J</sub> =25°C, I <sub>F</sub> =40A	—	41	—	nS
Q <sub>rr</sub>	Reverse Recovery Charge	di/dt=200A/us	—	350	—	nC
*Pulse Test: Pulse Width <= 300μs, Duty Cycle< =2%						

### Thermal Characteristic

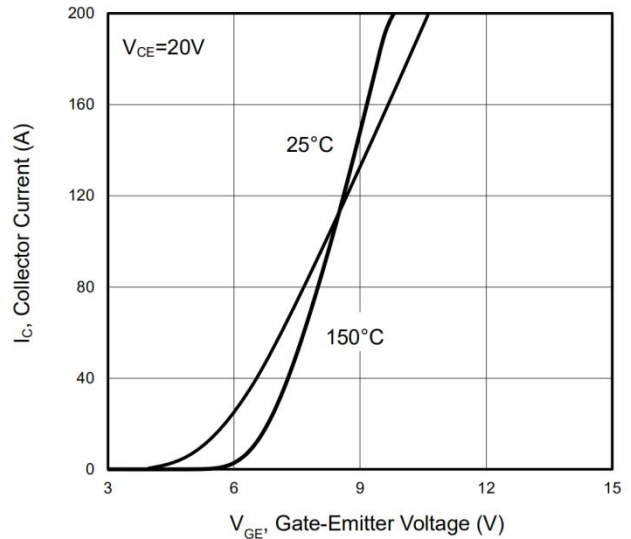
Symbol	Paramter	Typ	Max	Unit
$R_{\theta JC}$	Themal Resistance,Junction to case for IGBT	--	0.52	$^{\circ}C/W$
$R_{\theta JC}$	Themal Resistance,Junction to case for Diode	--	0.79	$^{\circ}C/W$
$R_{\theta JA}$	Themal Resistance,Junction to Ambient	--	40	$^{\circ}C/W$

### Typical Performance Characteristics

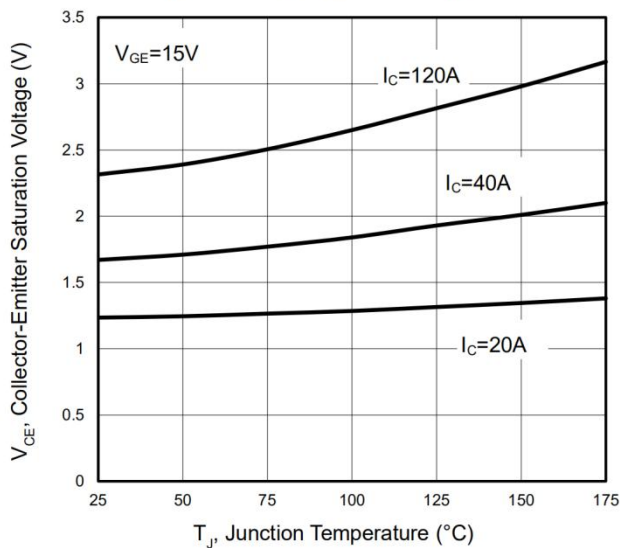
**Figure 1 Output Characteristics**



**Figure 2 Transfer Characteristics**



**Figure 3  $V_{CE(sat)}$  vs. Temperature**



**Figure 4 Saturation Voltage vs.  $V_{GE}$**

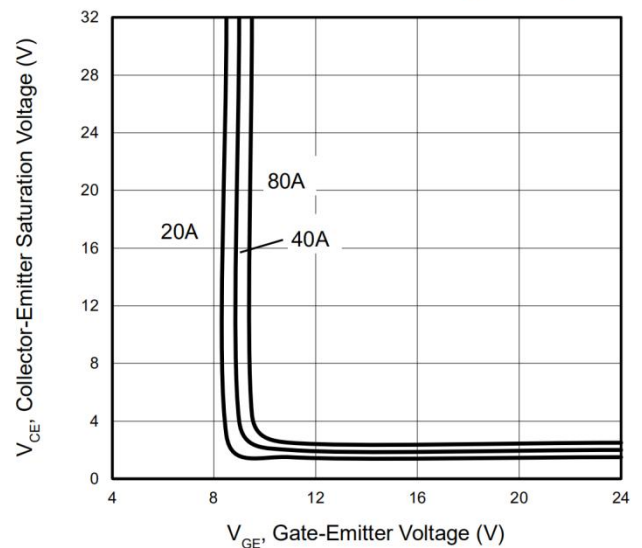


Figure 5 Capacitance Characteristics

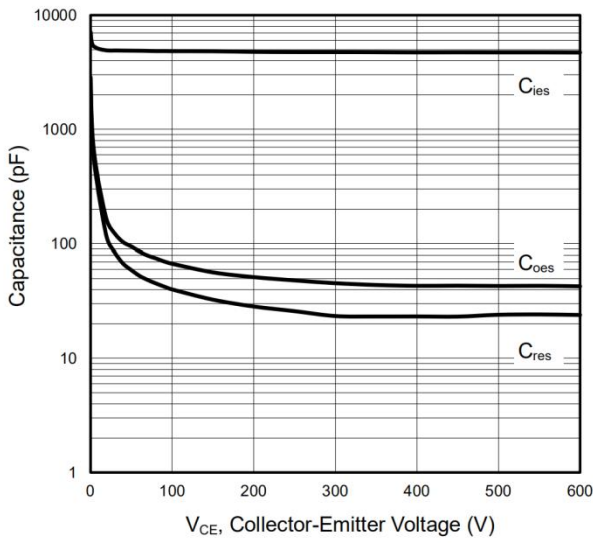


Figure 6 Gate Charge Wave Form

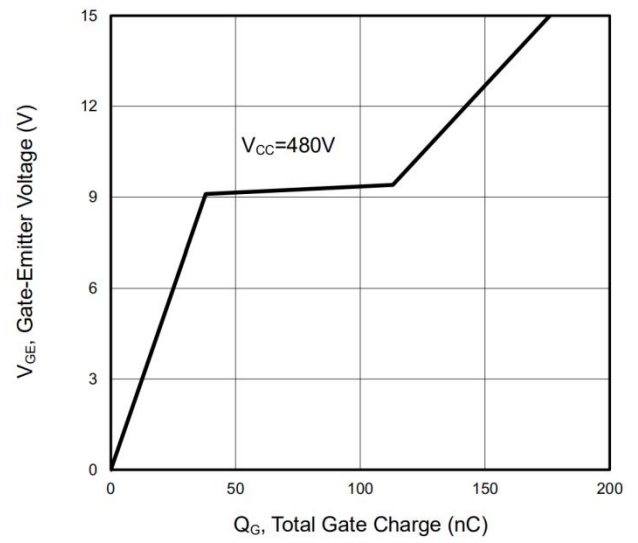


Figure 7 Forward Characteristics

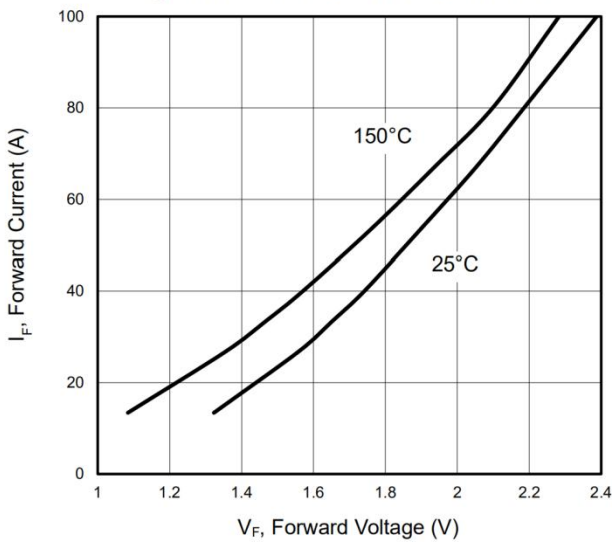


Figure 8 V\_F vs. Temperature

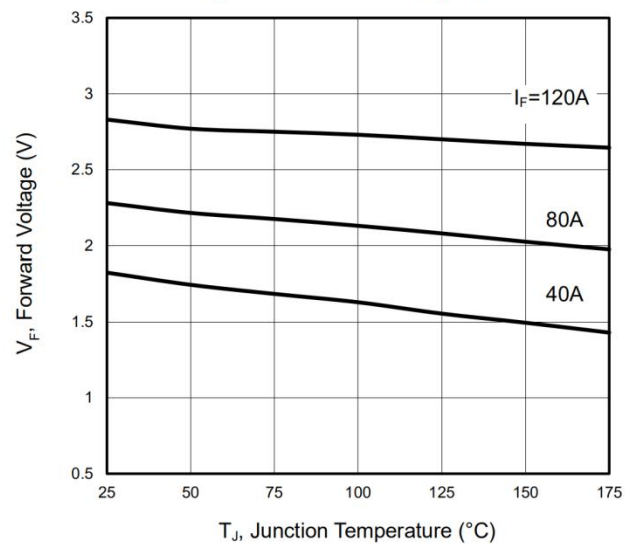


Figure 9 Switching Loss vs. R\_G

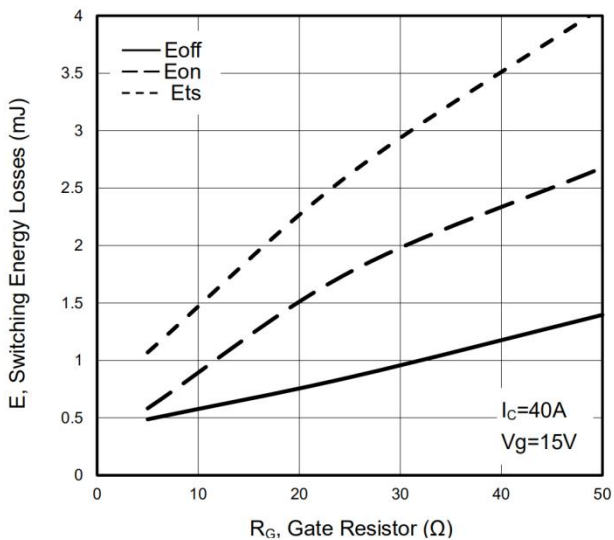


Figure 10 Switching Energy vs. Temperature

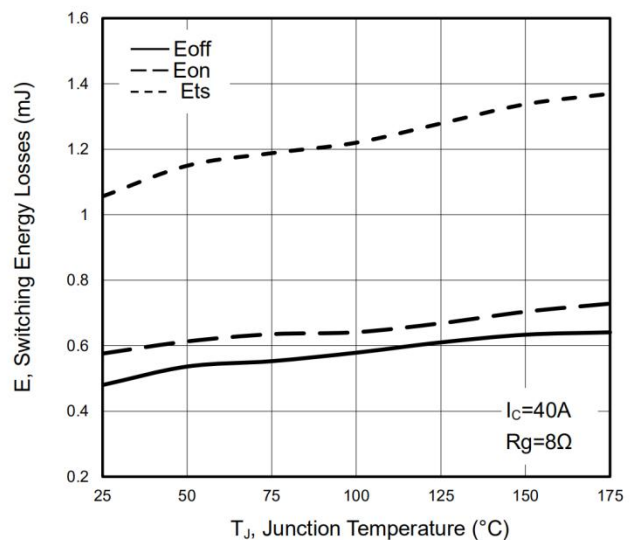


Figure 11 Switching Loss vs. Collector Current

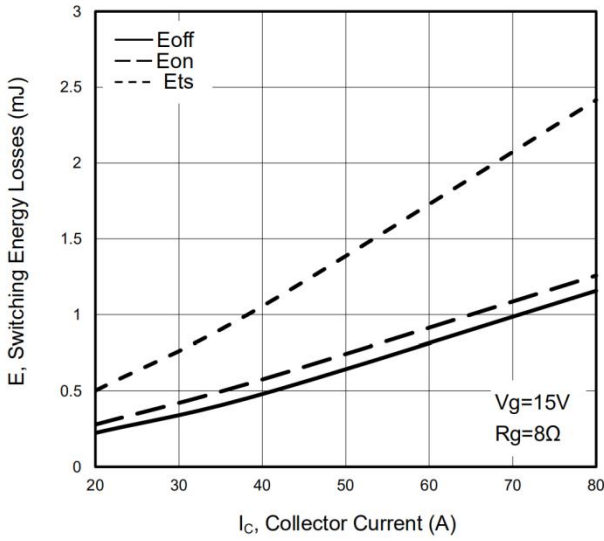


Figure 12 Switching Loss vs. Collector Current

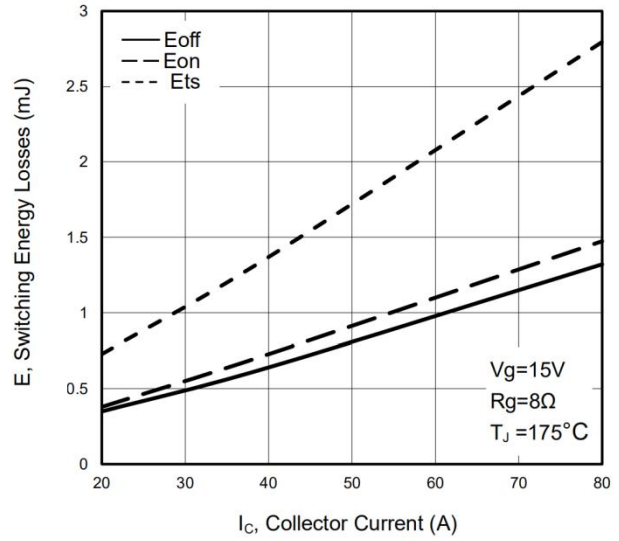


Figure 13  $V_{GE(th)}$  vs. Junction Temperature

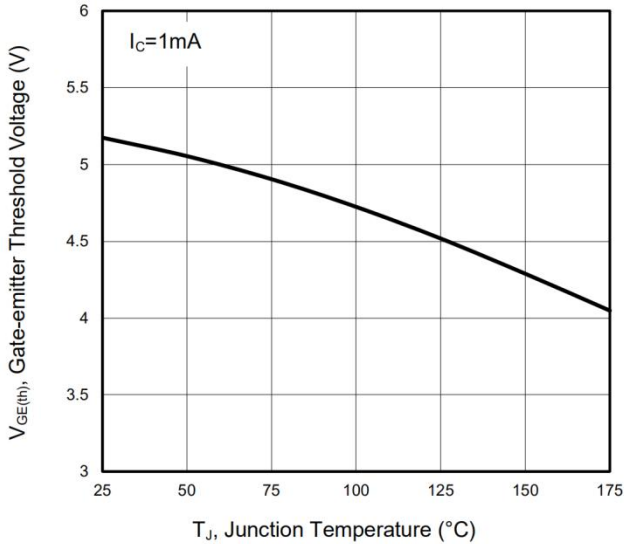


Figure 14  $V_{CE(sat)}$  vs. Collector Current

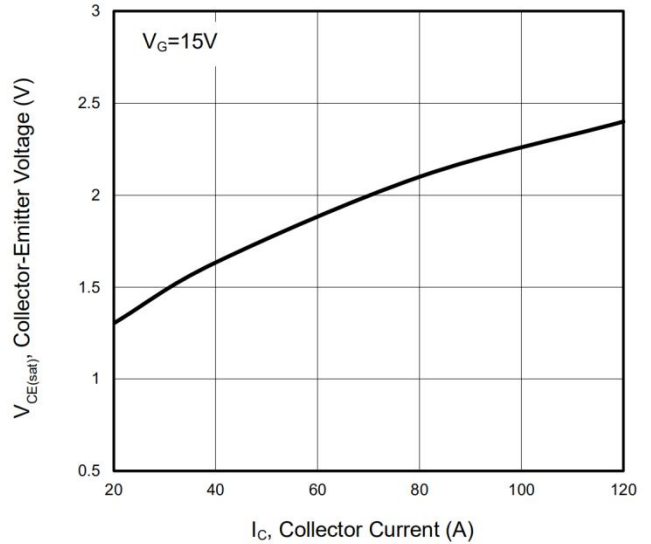


Figure 15 Forward Bias Safe Operating Area

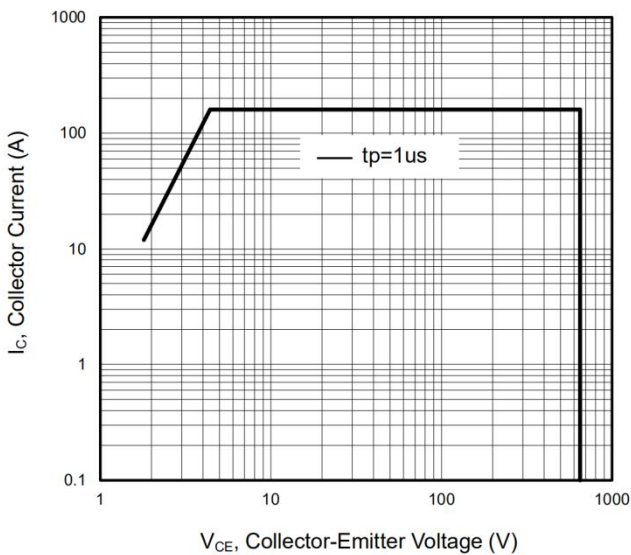


Figure 16  $P_{tot}$  vs. Case Temperature

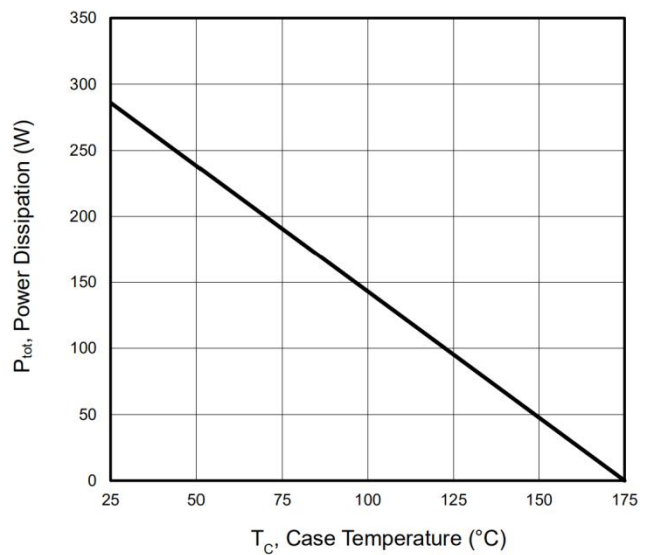


Figure 17  $V_{CES}$  vs. Temperature

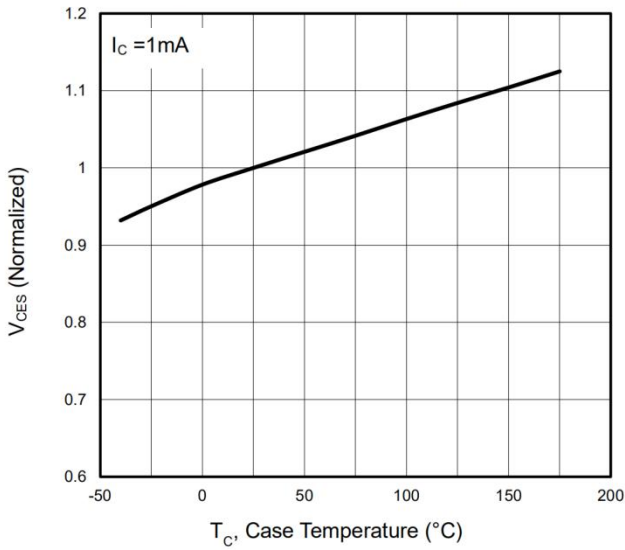


Figure 18  $I_C$  vs. Temperature

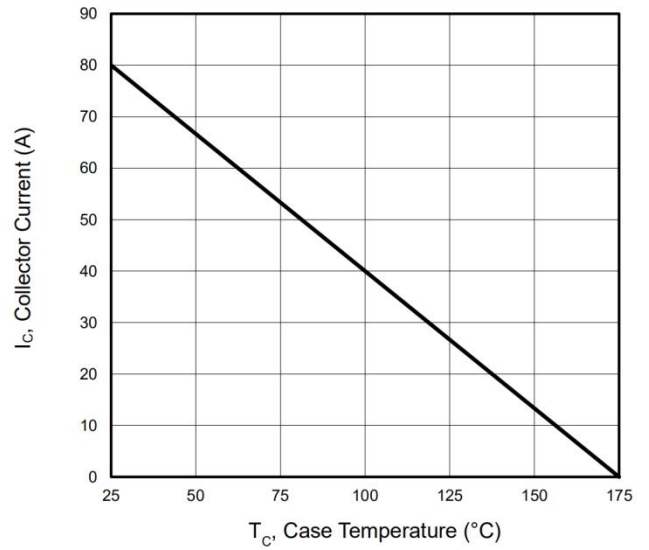


Figure 19 Switching Time vs.  $I_C$

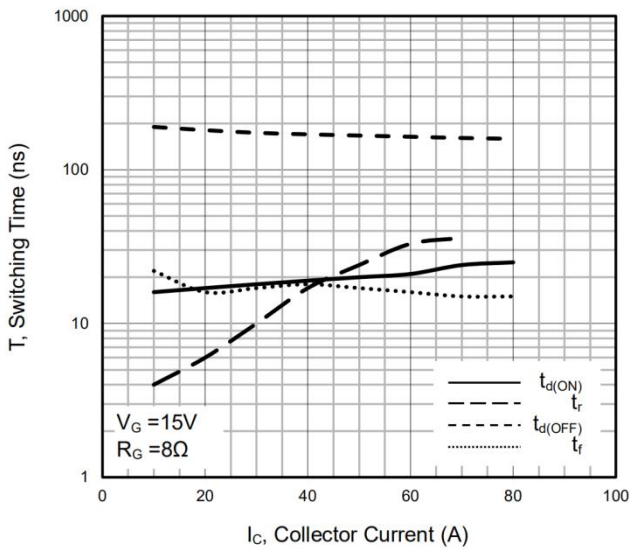


Figure 20 Switching Time vs.  $R_G$

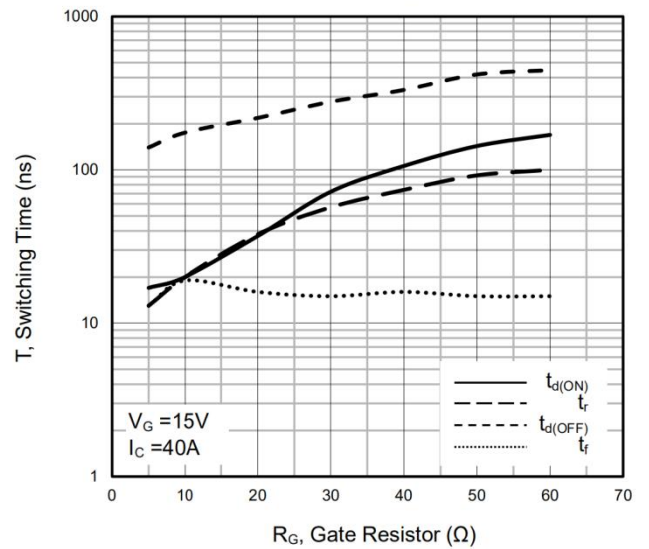


Figure 21 Switching Time vs.  $I_C$

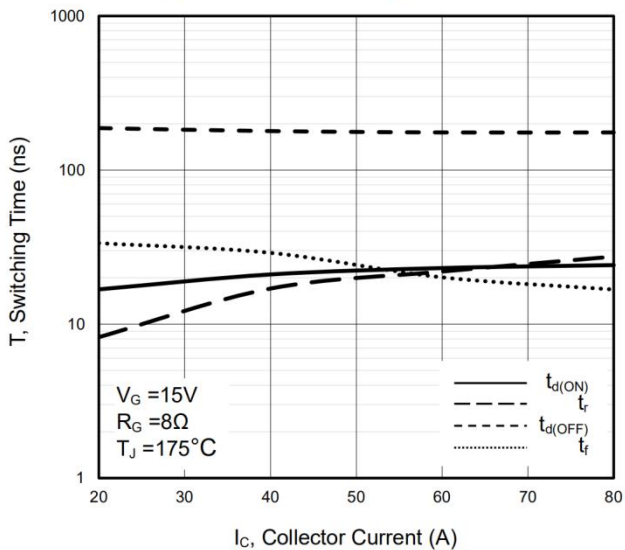
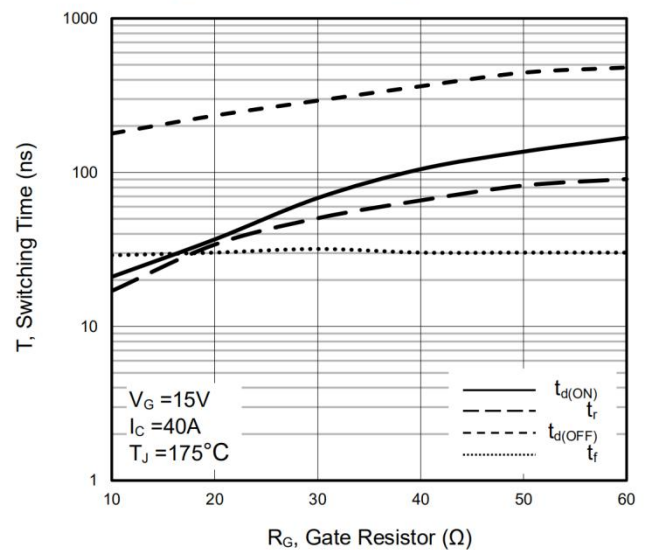


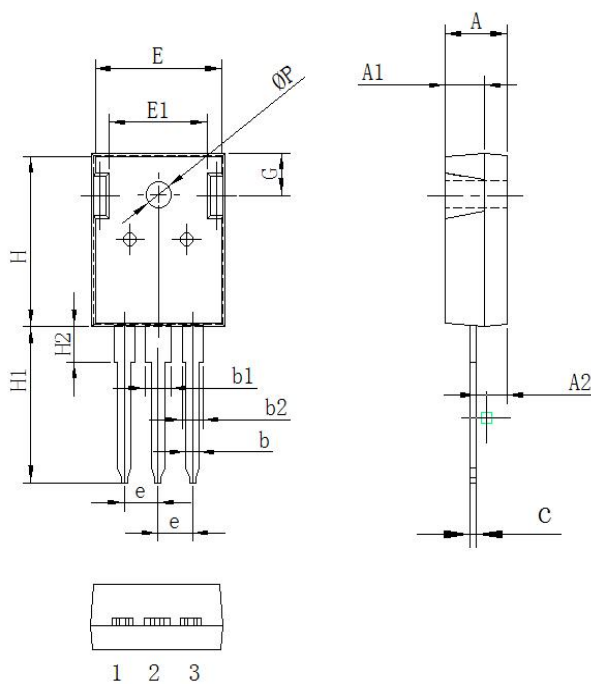
Figure 22 Switching Time vs.  $R_G$



## Package Information

### TO-247 PACKAGE

#### 基本尺寸



Symbol	单位 mm		
	Min	Nom	Max
A	4.8	5.00	5.20
A1	3.3	3.5	3.7
A2	2.20	2.40	2.60
b	1.00	1.2	1.40
b1	2.90	3.10	3.30
b2	1.90	2.10	2.30
c	0.50	0.60	0.70
e	5.25	5.45	5.65
E	15.2	15.7	16.2
E1	10.2	10.7	11.2
H	20.8	21	21.2
H1	19.5	20.0	20.5
H2	4.00	4.20	4.40
G	5.60	5.80	600
ΦP	3.50	3.70	3.90

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